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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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*G Denotes RoHS Compliant, Pb Free Terminal Finish.

ULTRAFAST SOFT RECOVERY RECTIFIER DIODE

PRODUCT APPLICATIONS

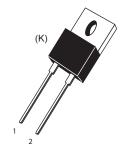
- Anti-Parallel Diode
 -Switchmode Power Supply
 - -Inverters
- Free Wheeling Diode
 - -Motor Controllers
 - -Converters
 - -Inverters
- · Snubber Diode
- PFC

PRODUCT FEATURES

- Ultrafast Recovery Times
- Soft Recovery Characteristics
- · Popular TO-220 Package
- · Low Forward Voltage
- Low Leakage Current
- Avalanche Energy Rated

PRODUCT BENEFITS

- Low Losses
- Low Noise Switching
- Cooler Operation
- · Higher Reliability Systems
- Increased System Power Density





- 1 Cathode
- 2 Anode

Back of Case - Cathode

MAXIMUM RATINGS

All Ratings: $T_C = 25$ °C unless otherwise specified.

| Symbol | Characteristic / Test Conditions | APT15DQ100K(G) | UNIT |
|----------------------------------|--|----------------|-------|
| V _R | Maximum D.C. Reverse Voltage | | |
| V _{RRM} | Maximum Peak Repetitive Reverse Voltage | 1000 | Volts |
| V _{RWM} | Maximum Working Peak Reverse Voltage | | |
| I _{F(AV)} | Maximum Average Forward Current (T _C = 126°C, Duty Cycle = 0.5) | 15 | |
| I _{F(RMS)} | RMS Forward Current (Square wave, 50% duty) | 29 | Amps |
| I _{FSM} | Non-Repetitive Forward Surge Current (T _J = 45°C, 8.3ms) | 80 | |
| E _{AVL} | Avalanche Energy (1A, 40mH) | 20 | mJ |
| T _J ,T _{STG} | Operating and StorageTemperature Range | -55 to 175 | ိုင |
| T _L | Lead Temperature for 10 Sec. | 300 | |

STATIC ELECTRICAL CHARACTERISTICS

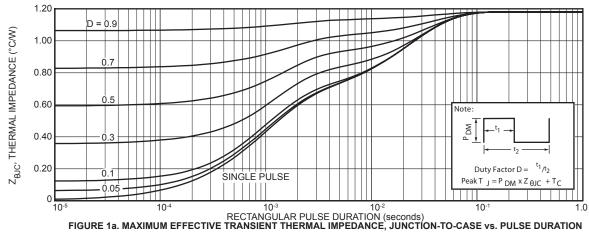
| Symbol | Characteristic / Test Conditions | | MIN | TYP | MAX | UNIT |
|-----------------|---|--|-----|------|-----|-------|
| V _F | Forward Voltage | I _F = 15A | | 2.5 | 3.0 | Volts |
| | | I _F = 30A | | 3.06 | | |
| | | I _F = 15A, T _J = 125°C | | 1.92 | | |
| I _{RM} | Maximum Reverse Leakage Current | V _R = 1000V | | | 100 | - μΑ |
| | | V _R = 1000V, T _J = 125°C | | | 500 | |
| C _T | Junction Capacitance, V _R = 200V | | | 12 | | pF |

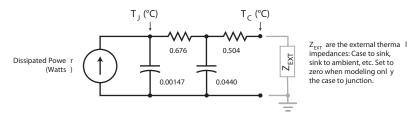
| Symbol | Characteristic | Test Conditions | MIN | TYP | MAX | UNIT |
|------------------|--|---|-----|------|-----|------|
| t _{rr} | Reverse Recovery Time $I_F = 1A$, $di_F/dt =$ | $-100A/\mu s$, $V_R = 30V$, $T_J = 25^{\circ}C$ | - | 20 | | ns |
| t _{rr} | Reverse Recovery Time | $I_F = 15A$, $di_F/dt = -200A/\mu s$ $V_R = 667V$, $T_C = 25^{\circ}C$ | - | 235 | | 115 |
| Q _{rr} | Reverse Recovery Charge | | - | 185 | | nC |
| I _{RRM} | Maximum Reverse Recovery Current | | - | 3 | - | Amps |
| t _{rr} | Reverse Recovery Time | $I_F = 15A$, $di_F/dt = -200A/\mu s$ $V_R = 667V$, $T_C = 125°C$ | - | 300 | | ns |
| Q _{rr} | Reverse Recovery Charge | | - | 810 | | nC |
| I _{RRM} | Maximum Reverse Recovery Current | | - | 6 | - | Amps |
| t _{rr} | Reverse Recovery Time | $I_F = 15A$, $di_F/dt = -1000A/\mu s$ $V_R = 667V$, $T_C = 125^{\circ}C$ | - | 125 | | ns |
| Q _{rr} | Reverse Recovery Charge | | - | 1150 | | nC |
| I _{RRM} | Maximum Reverse Recovery Current | | - | 19 | | Amps |

THERMAL AND MECHANICAL CHARACTERISTICS

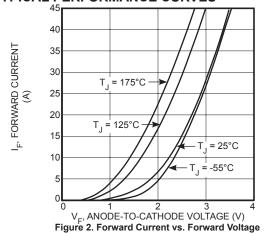
| Symbol | Characteristic / Test Conditions | MIN | TYP | MAX | UNIT |
|-----------------|-------------------------------------|-----|------|------|-------|
| $R_{\theta JC}$ | Junction-to-Case Thermal Resistance | | | 1.18 | °C/W |
| W _T | Package Weight | | 0.07 | | OZ |
| | | | 1.9 | | g |
| Torque | Maximum Mounting Torque | | | 10 | lb•in |
| | | | | 1.1 | N•m |

Microsemi reserves the right to change, without notice, the specifications and information contained herein.





TYPICAL PERFORMANCE CURVES



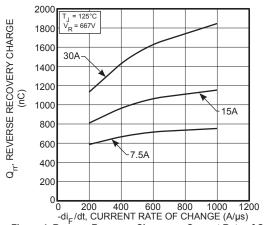
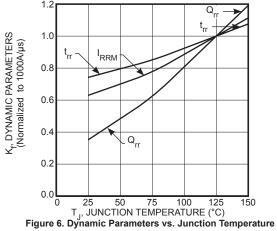
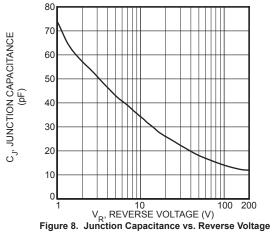


Figure 4. Reverse Recovery Charge vs. Current Rate of Change





APT15DQ100K(G)

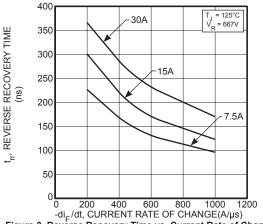


Figure 3. Reverse Recovery Time vs. Current Rate of Change

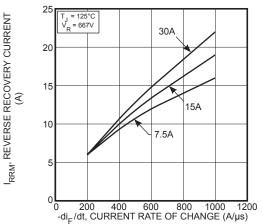


Figure 5. Reverse Recovery Current vs. Current Rate of Change

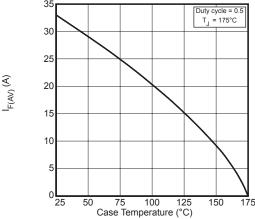


Figure 7. Maximum Average Forward Current vs. CaseTemperature

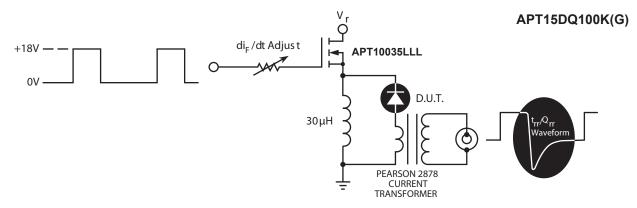
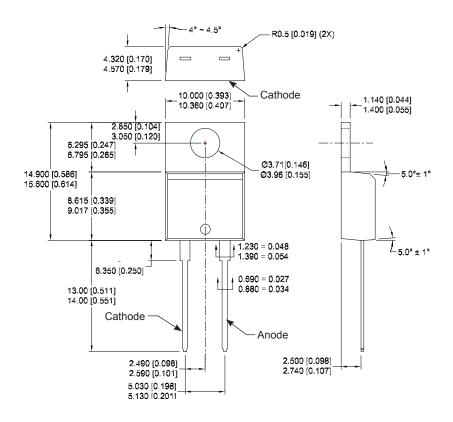


Figure 9. Diode Test Circuit

- I_F- Forward Conduction Current
 di_F/dt Rate of Diode Current Change Through Zero Crossing.
 I_{RRM} Maximum Reverse Recovery Current
 t_{rr} Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25, I_{RRM} passes through zero.
- f 5 $\,{\sf Q}_{\!_{
 m fr}}$ Area Under the Curve Defined by ${\sf I}_{\!_{
 m RRM}}$ and ${\sf t}_{\!_{
 m RR.}}$

Figure 10. Diode Reverse Recovery Waveform Definition

TO-220 (K) Package Outline e3 100% Sn



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